

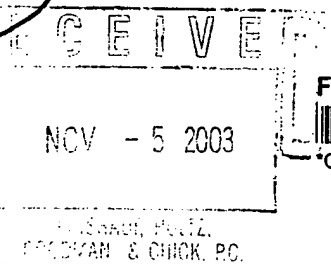


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CONFIRMATION NO. 1137

FILING RECEIPT



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Applicant(s)

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Assignment For Published Patent Application

Olympus Optical Co., Ltd., Tokyo, JAPAN;

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Early Publication Request: No

Title

Laser scanning microscope, semiconductor laser light source unit, scanning unit for a laser scanning microscope, and method of connecting semiconductor light source to scanning